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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/776,926	02/11/2004	Takahiro Yamaguchi	02008/092002	2381
7590	05/14/2007			
Jonathan P. Osha ROSENTHAL & OSHA L.L.P. Suite 2800 1221 McKinney St. Houston, TX 77010			EXAMINER BAYARD, EMMANUEL	
			ART UNIT 2611	PAPER NUMBER
			MAIL DATE 05/14/2007	DELIVERY MODE PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

<b>Office Action Summary</b>	<b>Application No.</b>	<b>Applicant(s)</b>	
	10/776,926	YAMAGUCHI ET AL.	
	<b>Examiner</b> Emmanuel Bayard	<b>Art Unit</b> 2611	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --  
**Period for Reply**

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

#### Status

- 1) Responsive to communication(s) filed on 11 February 2004.  
 2a) This action is FINAL.                    2b) This action is non-final.  
 3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

#### Disposition of Claims

- 4) Claim(s) 1-53 is/are pending in the application.  
 4a) Of the above claim(s) \_\_\_\_\_ is/are withdrawn from consideration.  
 5) Claim(s) 40-52 is/are allowed.  
 6) Claim(s) 1-15, 19-28, 33, 34, 36-39 and 53 is/are rejected.  
 7) Claim(s) 16-18, 29-32 and 35 is/are objected to.  
 8) Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

#### Application Papers

- 9) The specification is objected to by the Examiner.  
 10) The drawing(s) filed on \_\_\_\_\_ is/are: a) accepted or b) objected to by the Examiner.  
     Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).  
     Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).  
 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

#### Priority under 35 U.S.C. § 119

- 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).  
 a) All    b) Some \* c) None of:  
 1. Certified copies of the priority documents have been received.  
 2. Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.  
 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

\* See the attached detailed Office action for a list of the certified copies not received.

#### Attachment(s)

- 1) Notice of References Cited (PTO-892)  
 2) Notice of Draftsperson's Patent Drawing Review (PTO-948)  
 3) Information Disclosure Statement(s) (PTO/SB/08)  
     Paper No(s)/Mail Date \_\_\_\_\_
- 4) Interview Summary (PTO-413)  
     Paper No(s)/Mail Date. \_\_\_\_\_  
 5) Notice of Informal Patent Application  
 6) Other: \_\_\_\_\_

## DETAILED ACTION

### ***Claim Rejections - 35 USC § 102***

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

2. Claims 1, 19-20 are rejected under 35 U.S.C. 102(e) as being anticipated by Gauthier et al U.S. patent No 6,671,683 B2.

As per claim 1, Gauthier teaches measuring apparatus for measuring jitter transfer function of an electronic device, comprising: a timing jitter estimator operable to calculate an output timing jitter sequence of an output signal based on said output signal output (see figs. 5a-5b, 8 and abstract and col.1, lines 65-67 and col.2, lines 64-67 and col.3, lines 7-10 and col.9, lines 18-20, 48-50) a from said electronic device (see col.1, line 31); and a jitter transfer function estimator (col.5, lines 25-37) operable to calculate jitter transfer function of said electronic device based on said output timing jitter Sequence.

As per claims 19-20, Gauthier et al does teach Wherein said timing jitter estimator estimates timing jitter sequence of input data clock signal for generating input

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data signal given to said electronic device, and a timing jitter sequence of output data signal output from said electronic device in response to said input data signal, and said jitter transfer function measuring apparatus measures a jitter transfer function between said input data signal and said output data signal based on said timing jitter sequence estimated by said timing jitter estimator (see rejection of claim 1 above).

***Claim Rejections - 35 USC § 103***

1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

3. Claims 2-3 are rejected under 35 U.S.C. 103(a) as being unpatentable over Gauthier et al U.S. Patent No 6,671,863 B2 in view of Yang U.S. patent No 6,573,940 B1.

As per claim 2, Gauthier et al teaches all the features of the claimed invention except an instantaneous phase noise estimator operable calculate an instantaneous phase noise of said output signal based on said output signal; and a re-sampler operable to generate said output timing jitter sequence obtained by re-sampling said instantaneous phase noise at predetermined timings.

Yang teaches an instantaneous phase noise estimator operable calculate an instantaneous phase noise of said output signal based on said output signal (see col.23, lines 15-60); and a re-sampler operable to generate said output timing jitter sequence

obtained by re-sampling said instantaneous phase noise at predetermined timings (see col.23, lines 15-60).

It would have been obvious to one of ordinary skill in the art to implement the teaching of Yang into Gauthier as to acquire higher quality video signals as taught by Yang (see col.23, line 40).

As per claim 3, Yang teaches a re-sampler re-samples said instantaneous phase noise (see col.23, lines 15-63). Furthermore implementing such teaching into Gauthier at timings approximately same as zero-crossing timings of said output signal would have been obvious to one skilled in the art as to acquire higher quality video signals as taught by Yang (see col.23, line 40).

#### ***Claim Rejections - 35 USC § 103***

4. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

5. Claims 4-15, 21-24, 36, are rejected under 35 U.S.C. 103(a) as being unpatentable over Gauthier et al U.S. Patent No 6,671,863 B2 in view of Choudhary U.S. patent No 6,782,404 B2.

As per claims 4-5, Gauthier teaches all the features of the claimed invention except receiving a plurality of input signals having and outputs a plurality of said output signals to respectively corresponding input signals.

Choudhary teaches A measuring apparatus as claimed in claim 1, wherein said electronic device receives a plurality of input signals having different jitter amounts and outputs said plurality of output signals respectively corresponding to said plurality of input signals, (see abstract and figs.7, 10 and col.2, lines 12-25 and col.4, lines 32-35 and col.7, lines 30-55) said timing jitter estimator calculates said output timing jitter sequences corresponding to said output signals respectively, and said jitter transfer function estimator calculates said jitter transfer function further based on said information indicating a plurality of input timing jitter sequences (see fig.7).

It would have been obvious to one of ordinary skill in the art to incorporate the teaching of Choudhary et al into Gauthier as to provide a jitter tolerant system which users could program by supplying appropriate values to eliminate noise effects as taught by Choudhary (see col.7, lines 34-40).

As per claim 6, Gauthier teaches a frequency-domain (see col.2, line 9). Furthermore implementing such teaching in combination with Choudhary as to transform said input timing jitter sequences and said output timing jitter sequences to frequency domain signals would have been obvious to one skilled in the art as to provide a jitter tolerant system which users could program by supplying appropriate values to eliminate noise effects as taught by Choudhary (see col.7, lines 34-40).

As per claims 7, 8, 10-11, Gauthier teaches jitter transfer function estimator comprises jitter gain estimator operable to calculate a gain ( $H_j(f_j)$ ) of said jitter transfer function (see col.5, lines 17-37). Furthermore implementing such gain to generate the following Equation would have been obvious to one skilled in the art as to optimize the PLL loop bandwidth related to balancing the effect of input jitter with the PLL loop's speed of response to compensate for output jitter induced by power supply noise.

As per claim 9, Gauthier teaches wherein said jitter gain estimator calculates said gain of said jitter transfer function based on a result of linear fitting relationship between a peak-to-peak value of an input timing jitter (see col.4, lines 24-25 and col.5, lines 17-50). Furthermore implementing such gain to and peak-peak value of said plurality of input timing jitter sequences to generate an output timing jitter of said plurality of output timing jitter sequences, or a root-mean-square (RMS) value of said output timing jitter said output timing jitter sequences and a root -mean-square value of an input timing jitter of said plurality of input timing jitter sequences would have been obvious to one skilled in the art as to optimize the PLL loop bandwidth related to balancing the effect of input jitter with the PLL loop's speed of response to compensate for output jitter induced by power supply noise.

As per claim 12, would include wherein said jitter applying unit applies a sinusoidal jitter to said input signal as said input timing jitter. as to optimize the PLL loop bandwidth related to balancing the effect of input jitter with the PLL loop's speed of response to compensate for output jitter induced by power supply noise.

As per claim 13, Gauthier would include wherein said jitter applying unit applies said input timing jitter by modulating a phase of said input signal as to optimize the PLL loop bandwidth related to balancing the effect of input jitter with the PLL loop's speed of response to compensate for output jitter induced by power supply noise.

As per claim 14, wherein said jitter applying unit applies said input timing jitter by modulating frequency of said input signal as to optimize the PLL loop bandwidth related to balancing the effect of input jitter with the PLL loop's speed of response to compensate for output jitter induced by power supply noise.

As per claims 15 and 21-22, Choudhary teaches a clock recovery unit operable to generate a recovered clock signal of said output signal based on said output signal, wherein said timing jitter estimator estimates said output (see fig.7). Furthermore implementing such teaching into Gauthier as to generate accurate time synchronization throughout the network.

As per claims 23-24, Choudhary teaches receives serial data as said input data, and outputs a parallel data (see fig.7) Furthermore implementing such teaching into Gauthier for generating output data signal from output pins , the number of output pins being predetermined, said timing jitter estimator estimates said output timing jitter sequence of said output data signal according to data output from a certain output pin out of said output pins, and said input unit supplies said input data signal to said electronic device , in which a bit of the pattern data corresponding to the certain output pin out of said output pins repeats 1 (high) and 0 (low) by turns as to optimize the PLL

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loop bandwidth related to balancing the effect of input jitter with the PLL loop's speed of response to compensate for output jitter induced by power supply noise.

As per claim 36, Gauthier teaches a measuring apparatus for measuring jitter transfer function of an electronic device, comprising: a timing jitter estimator operable to calculate an output timing jitter sequence of an output signal based on said output signal output (see figs. 5a-5b, 8 and abstract and col.1, lines 65-67 and col.2, lines 64-67 and col.3, lines 7-10 and col.9, lines 18-20, 48-50) a from said electronic device (see col.1, line 31); and a jitter transfer function estimator (col.5, lines 25-37) operable to calculate jitter transfer function of said electronic device based on said output timing jitter Sequence.

However Gauthier does not teaches receiving a plurality of input signals having and outputs a plurality of said output signals to respectively corresponding input signals.

Choudhary teaches A measuring apparatus as claimed in claim 1, wherein said electronic device receives a plurality of input signals having different jitter amounts and outputs said plurality of output signals respectively corresponding to said plurality of input signals, (see abstract and figs.7, 10 and col.2, lines 12-25 and col.4, lines 32-35 and col.7, lines 30-55) said timing jitter estimator calculates said output timing jitter sequences corresponding to said output signals respectively, and said jitter transfer function estimator calculates said jitter transfer function further based on said information indicating a plurality of input timing jitter sequences (see fig.7).

It would have been obvious to one of ordinary skill in the art to incorporated the teaching of Choudhary et al into Gauthier as to provide a jitter tolerant system which

users could program by supplying appropriate values to eliminate noise effects as taught by Choudhary (see col.7, lines 34-40).

***Claim Rejections - 35 USC § 103***

1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

2. Claims 25-26 and 37 are rejected under 35 U.S.C. 103(a) as being unpatentable over Dalmia et al U.S. patent No 5,835,501 in view of Dykes et al U.S. Pub No 2002/0032832 B1.

As per claims 25 and 37, Dalmia et al teaches a measuring apparatus for measuring a bit error rate of device, comprising a bit error rate estimator operable to estimate said bit error rate (see figs. 2 and 4 element 3 and col.3, lines 13-15) of said device based on a gain of jitter transfer function of said device (see fig.3 and col.2, lines 33-52 and col.3, lines 33-40 and col.6, lines 6-9, 48 and col.7, lines 15-21).

However Dalmia et al does not teach measuring the bit error rate based on an electronic device.

Dykes et al teach measuring the bit error rate based on an electronic device (see page 6, [0084]).

It would have been obvious to one of ordinary skill in the art to implement the teaching of Dykes into Dalmia as to determine the optimal operating parameters of the electronic device as taught by Dykes (see col.6, [0084]).

As per claim 26, Dalmia does teach wherein said bit error rate estimator estimates said bit error rate further based on a phase of said jitter transfer function (see col.3, line 22).

Dykes et al teach measuring the bit error rate based on an electronic device (see page 6, [0084]).

***Claim Rejections - 35 USC § 103***

2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

3. Claims 27-28 and 38 are rejected under 35 U.S.C. 103(a) as being unpatentable over Dalmia et al U.S. patent No 5,835,501 in view of Walker Pub No 2001/0011893 A1.

As per claims 27 and 38, Dalmia teaches a measuring apparatus for measuring jitter tolerance of an electronic device, comprising a jitter tolerance estimator operable to estimate said jitter tolerance of said device based on a gain of jitter transfer function of said device (see col.2., lines 26-35, 45-52 and col.3, line 33-40 and col.4, lines 21-27, 64-67).

However Dalmia et al does not teaches measuring the jitter tolerance based on an electronic device.

Walker teaches measuring the jitter tolerance based on an electronic device (see abstract).

It would have been obvious to one of ordinary skill in the art to implement the teaching of Walker into Dalmia as to determine timing error between the expected or ideal timing of a signal and the actual timing of a signal which the characteristics of the timing error change with time as taught by Walker (see abstract).

As per claim 28, Dalmia and Walker in combination would teach wherein said jitter tolerance estimator estimates said jitter tolerance further based on a phase of said jitter transfer function as to determine timing error between the expected or ideal timing of a signal and the actual timing of a signal which the characteristics of the timing error change with time as taught by Walker (see abstract).

#### ***Claim Rejections - 35 USC § 103***

4. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

5. Claims 33-34 and 39 rejected under 35 U.S.C. 103(a) as being unpatentable over Roberts et al U.S. Patent No 6,735,259 B1 in view of Dykes et al U.S. Pub No 2002/0032832 A1.

As per claims 33 and 39, Roberts et al teaches measuring apparatus a device, comprising: a timing estimator operable to estimate an input timing sequence of an input signal for testing said device and an output timing sequence of an output signal output from said device in response to said input signal (see figs.1, 3b, 4 and col.1, lines 25-35 and col.4, lines 65-67 and col.6, lines 4-5, 61-62 and col.7, lines 10-15 and col.9, lines 50-55); a timing difference estimator operable to calculate timing differences between said input timing sequence and said output timing sequence (see figs. 1, 3b , 4 element 6 and col.9, lines 35-53).; and a bit error rate estimator operable to estimate said bit error rate of said device based on said timing differences (see figs. 1, 3b, 4 element 12 and col.5, lines 18-22 and col.6, lines 64-67).

However Roberts et al does not teach measuring the bit error rate based on an electronic device.

Dykes et al teach measuring the bit error rate based on an electronic device (see page 6, [0084]).

It would have been obvious to one of ordinary skill in the art to implement the teaching of Dykes into Roberts as to determine the optimal operating parameters of the electronic device as taught by Dykes (see col.6, [0084]).

As per claim 34, Dalmia and Dykes in combination would teach wherein said timing estimator estimates said input timing sequence and said output timing sequence based on a zero-crossing timing sequence of rising edges or falling edges of said input signal and said output signal as to determine the optimal operating parameters of the electronic device as taught by Dykes (see col.6, [0084]).

***Claim Rejections - 35 USC § 103***

6. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

Claim 53 is rejected under 35 U.S.C. 103(a) as being unpatentable over Gauthier et al U.S. Patent No 6,671,863 B2 in view of Eubanks U.S. Pub 2003/0063701 A1.

As per claim 53, Gauthier teaches measuring apparatus for measuring jitter transfer function of an electronic device, comprising: a timing jitter estimator operable to estimate an output timing jitter sequence of an output signal based on said output signal output (see figs. 5a-5b, 8 and abstract and col.1, lines 65-67 and col.2, lines 64-67 and col.3, lines 7-10 and col.9, lines 18-20, 48-50) from said electronic device (see col.1, line 31); and a jitter transfer function measuring (col.5, lines 25-37) operable to measure jitter transfer function of said electronic device based on said output timing jitter Sequence.

However Gauthier does not teach a timing jitter estimator to estimating an output instantaneous phase noise and to measure a jitter transfer function based on said instantaneous phase noise.

Eubanks et al teaches a timing jitter estimator to estimating an output instantaneous phase noise and to measure a jitter transfer function based on said instantaneous phase noise (see figs. 2-4, 8 and page 2, paragraph [0031] and page 3 paragraph [0046] and page 5, paragraph [0089]).

It would have been obvious to one of ordinary skill in the art to implement the teaching of Eubanks into Gauthier as to correctly filter out the jitter from the clock to allow the clock to be used as a system clock as taught by Eubanks (see abstract and page 3, paragraph [0046].

***Allowable Subject Matter***

7. Claims 16-18, 29-32, and 35 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.
8. Claims 40-52 are allowed.
9. The following is a statement of reasons for the indication of allowable subject matter: The recited prior arts fail to anticipate or render obvious the following recited features: An analytic signal transformer operable to transform said output signal to complex analytic signal; an instantaneous phase estimator operable to estimate an instantaneous phase of said analytic signal based on said analytic signal; a linear instantaneous phase estimator operable to estimate a linear instantaneous phase of said output signal based on an instantaneous phase of said analytic signal as recited in claim 16. An analytic signal transformer operable to transform said output signal to complex analytic signal; an instantaneous phase estimator operable to estimate an instantaneous phase of said analytic signal based on said analytic signal as recited in claim 33. A jitter related transmission penalty estimator operable to estimate said

reliability of said electronic device against jitter based on said jitter distortion as recited claim 38. A jitter distortion estimator operable to estimate jitter distortion of an output timing jitter of said output signal output from said electronic device according to said first check signal, against an ideal timing jitter of said output signal which said electronic device is to output according to said first check signal; and a judging unit operable to judge whether said jitter tolerance is a right value based on said jitter distortion as recited in claim 57.

### ***Conclusion***

10. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Roberts et al U.S. Patent No 6,735,259 B1 teaches a method and apparatus for optimization of a data communication. (\*) .

Dalmia et al U.S. patent No 5,835,501 teaches a built-in test scheme (\*).

Tabatabaei et al U.S. patent No 6,754,613 B2 teaches a high-resolution time-to-digital converter.

Gauthier et al U.S. patent No 6,664,828 B2 teaches a post-silicon control.

O'Brien et al U.S. patent No 6,356,126 B1 teaches a Low jitter phase locked loop.

Wong U.S. patent No 6,697,445 B1 teaches a method and apparatus with enhance jitter.

Kyodo U.S. patent No 5,796,231 teaches a rotation position.

Niijima U.S. patent no 6,768,9554 B2 teaches a jitter quantity calculator.

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Caresslo et al U.S. patent No 5,872,819 teaches a method and apparatus for facilitating symbol timing.

Bulzachelli U.S. patent No 5,036,298 teaches a clock recovery circuit.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Emmanuel Bayard whose telephone number is 571 272 3016. The examiner can normally be reached on Monday-Friday (7:Am-4:30PM) Alternate Friday off.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Jay Patel can be reached on 571 272 2988. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

5/7/2007

Emmanuel Bayard  
Primary Examiner  
Art Unit 2611

EMMANUEL BAYARD  
PRIMARY EXAMINER

